## **Special Issue**

## Application of X-ray Computed Tomography

## Message from the Guest Editors

We are inviting submissions to this Special Issue on the "Application of X-ray Computed Tomography". X-ray computed tomography is a widespread analysis technique. The spectrum of its applications ranges from medicine to metallurgy, microelectronics, geoscience, material science, engineering, 3D printing, etc. Its very high spatial and temporal resolution, together with its non-invasive character, makes X-ray computed tomography the best option of analysis in many cases. In this Special Issue, we invite authors to present their latest cutting-edge research in the field. Prof. Dr. Risco Ramon

### **Guest Editors**

Prof. Dr. Ramon Risco

Centro Nacional de Aceleradores, Universidad de Sevilla, 41092 Sevilla, Spain

Dr. Jing Qu

Advanced Materials Characterization Laboratory, University of Delaware, Newark, DE 19716, USA

## Deadline for manuscript submissions

closed (20 August 2023)



# Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5 CiteScore 5.5



## mdpi.com/si/116156

Applied Sciences Editorial Office MDPI, Grosspeteranlage 5 4052 Basel, Switzerland Tel: +41 61 683 77 34 applsci@mdpi.com

mdpi.com/journal/applsci





## Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5 CiteScore 5.5



## **About the Journal**

## Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

## **Editor-in-Chief**

Prof. Dr. Giulio Nicola Cerullo

Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

### **Author Benefits**

## **Open Access:**

free for readers, with article processing charges (APC) paid by authors or their institutions.

### **High Visibility:**

indexed within Scopus, SCIE (Web of Science), Ei Compendex, Inspec, CAPlus / SciFinder, and other databases.

#### Journal Rank:

JCR - Q2 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering)

